



TekExpress USB 3.1 Report

Test Report

Execution and Setup Information

DUT ID	DUT001	DUT Type	Host
Date/Time	2019-01-20 19:48:57	Scope Model	DSA71604C
Test Point	Compliance (TP1) - Far End	Scope Serial Numer	C130125
Connector Type	Standard	Scope F/W Version	10.5.1 Build 24
Channel Type	Both Long & Short	SPC Factory:S/W Calibration	PASS;PASS
Toggle Tool	Do not use	TekExpress Version	USB:10.3.1.21 Framework:4.2.7.301
Acquisition Mode	Live	DPOJET Version	"10.0.2.1"
SigTest Version	3.2.11(Gen1)	CTS Version	v1.0
Total Acquisition Time	2 Minutes 34 Seconds		
Total Analysis Time	1 Minute 55 Seconds		
Over All Test Result	Pass		
DUT COMMENT:	General Comment - USB3.1 DUT		

UI-Unit Interval									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
UI-Unit Interval	Lane1	Short	Gen1	SigTest	200.459 ps	Pass	518.740 fs & 601.260 fs	199.94 ps	201.06 ps
UI-Unit Interval	Lane1	Long	Gen1	SigTest	200.451 ps	Pass	511.173 fs & 608.827 fs	199.94 ps	201.06 ps
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-17								

Rj-Tx random jitter-Dual Dirac									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
Rj-Tx random jitter-Dual Dirac	Lane1	Short	Gen1	SigTest	1.502 ps	Informative	1.502 ps & 1.768 ps	0 s	3.27 ps
Rj-Tx random jitter-Dual Dirac	Lane1	Long	Gen1	SigTest	1.509 ps	Informative	1.509 ps & 1.761 ps	0 s	3.27 ps
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-19								

Mask Hits									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
Mask Hits	Lane1	Short	Gen1	SigTest	0.000	Pass	0.000	N.A	0
Mask Hits	Lane1	Long	Gen1	SigTest	0.000	Pass	0.000	N.A	0
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-18								

TSSC-Freq-Dev-Max									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
TSSC-Freq-Dev-Max (Max)	Lane1	Short	Gen1	DPOJET	-4.682 kppm (Max)	Pass	617.998 ppm & 982.002 ppm	-5.3 kppm	-3.7 kppm
TSSC-Freq-Dev-Max (Min)	Lane1	Short	Gen1	DPOJET	-4.744 kppm (Min)	Pass	556.390 ppm & 1.044 kppm	-5.3 kppm	-3.7 kppm
TSSC-Freq-Dev-Max (Max)	Lane1	Long	Gen1	DPOJET	-4.692 kppm (Max)	Pass	607.927 ppm & 992.073 ppm	-5.3 kppm	-3.7 kppm
TSSC-Freq-Dev-Max (Min)	Lane1	Long	Gen1	DPOJET	-4.783 kppm (Min)	Pass	516.967 ppm & 1.083 kppm	-5.3 kppm	-3.7 kppm
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-16								

TSSC-Freq-Dev-Min									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
TSSC-Freq-Dev-Min	Lane1	Short	Gen1	DPOJET	103.621 ppm (Max)	Pass	403.621 ppm & 196.379	-300.0 ppm	300.0 ppm

(Max)							ppm		
TSSC-Freq-Dev-Min (Min)	Lane1	Short	Gen1	DPOJET	36.179 ppm (Min)	Pass	336.179 ppm & 263.821 ppm	-300.0 ppm	300.0 ppm
TSSC-Freq-Dev-Min (Max)	Lane1	Long	Gen1	DPOJET	119.810 ppm (Max)	Pass	419.810 ppm & 180.190 ppm	-300.0 ppm	300.0 ppm
TSSC-Freq-Dev-Min (Min)	Lane1	Long	Gen1	DPOJET	54.616 ppm (Min)	Pass	354.616 ppm & 245.384 ppm	-300.0 ppm	300.0 ppm
COMMENTS		USB 3.1 Specification, Rev 1.0, Table 6-16							

TSSC-Mod-Rate - SSC Modulation rate									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
TSSC-Mod-Rate - SSC Modulation rate	Lane1	Short	Gen1	DPOJET	31.250 kHz	Pass	1.250 kHz & 1.750 kHz	30.0 kHz	33.0 kHz
TSSC-Mod-Rate - SSC Modulation rate	Lane1	Long	Gen1	DPOJET	31.238 kHz	Pass	1.238 kHz & 1.762 kHz	30.0 kHz	33.0 kHz
COMMENTS		USB 3.1 Specification, Rev 1.0, Table 6-16							

DJ-Tx deterministic Jitter-Dual Dirac									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
DJ-Tx deterministic Jitter-Dual Dirac	Lane1	Short	Gen1	SigTest	37.896 ps	Pass	37.896 ps & 48.104 ps	0 s	86.0 ps
DJ-Tx deterministic Jitter-Dual Dirac	Lane1	Long	Gen1	SigTest	45.976 ps	Pass	45.976 ps & 40.024 ps	0 s	86.0 ps
COMMENTS		USB 3.1 Specification, Rev 1.0, Table 6-19							

TJ-Tx total jitter-Dual Dirac at 1E-12 BER									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
TJ-Tx total jitter-Dual Dirac at 1E-12 BER	Lane1	Short	Gen1	SigTest	59.008 ps	Pass	59.008 ps & 72.992 ps	0 s	132.0 ps
TJ-Tx total jitter-Dual Dirac at 1E-12 BER	Lane1	Long	Gen1	SigTest	67.188 ps	Pass	67.188 ps & 64.812 ps	0 s	132.0 ps
COMMENTS		USB 3.1 Specification, Rev 1.0, Table 6-19							

Eye Height - Transmitter Eye Mask									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
Eye Height - Transmitter Eye Mask	Lane1	Short	Gen1	SigTest	218.620 mV	Pass	118.620 mV & 981.380 mV	100.0 mV	1.2 V
Eye Height - Transmitter Eye Mask	Lane1	Long	Gen1	SigTest	100.072 mV	Pass	72.369 uV & 1.100 V	100.0 mV	1.2 V
COMMENTS		USB 3.1 Specification, Rev 1.0, Table 6-19							

Eye Width @ 1E-12 BER									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
Width@BER	Lane1	Short	Gen1	SigTest	140.992 ps	Pass	72.992 ps	68.0 ps	N.A
Width@BER	Lane1	Long	Gen1	SigTest	132.812 ps	Pass	64.812 ps	68.0 ps	N.A
COMMENTS		USB 3.1 Specification, Rev 1.0, Table 6-18							

LFPS Duty Cycle									
Measurement	Lane	Channel	Generation	Method	Measured	Test Result	Margin	Low Limit	High Limit

Details					Value				
LFPS Duty Cycle (Max)	Lane1	Short	Gen1	SigTest	50.016 % (Max)	Pass	10.016 % & 9.984 %	40.0 %	60.0 %
LFPS Duty Cycle (Min)	Lane1	Short	Gen1	SigTest	49.987 % (Min)	Pass	9.987 % & 10.013 %	40.0 %	60.0 %
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-28								

LFPS Fall Time									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
LFPS Fall Time	Lane1	Short	Gen1	SigTest	949.682 ps	Pass	3.050 ns	N.A	4.0 ns
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-28								

LFPS Rise Time									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
LFPS Rise Time	Lane1	Short	Gen1	SigTest	970.441 ps	Pass	3.030 ns	N.A	4.0 ns
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-28								

LFPS TPeriod									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
LFPS TPeriod (Max)	Lane1	Short	Gen1	SigTest	64.289 ns (Max)	Pass	44.289 ns & 35.711 ns	20.0 ns	100.0 ns
LFPS TPeriod (Min)	Lane1	Short	Gen1	SigTest	64.067 ns (Min)	Pass	44.067 ns & 35.933 ns	20.0 ns	100.0 ns
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-28								

LFPS Vcm-AC									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
LFPS Vcm-AC	Lane1	Short	Gen1	SigTest	34.000 mV	Pass	66.000 mV	N.A	100.0 mV
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-28								

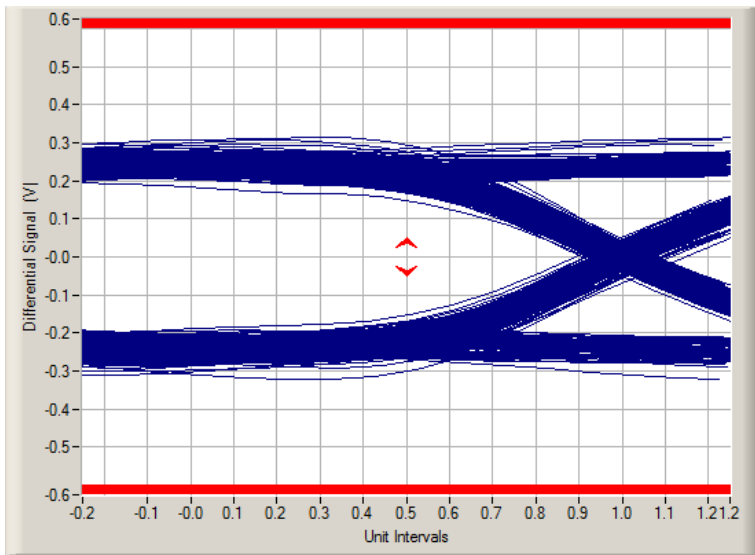
LFPS Vtx-DIFF-PP									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
LFPS Vtx-DIFF-PP (Max)	Lane1	Short	Gen1	SigTest	1.164 V (Max)	Pass	364.000 mV & 36.000 mV	800.0 mV	1.2 V
LFPS Vtx-DIFF-PP (Min)	Lane1	Short	Gen1	SigTest	1.140 V (Min)	Pass	340.000 mV & 60.000 mV	800.0 mV	1.2 V
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-28								

LFPS TBurst									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
LFPS TBurst (Max)	Lane1	Short	Gen1	SigTest	1.142 us (Max)	Pass	541.560 ns & 258.440 ns	600.0 ns	1.4 us
LFPS TBurst (Min)	Lane1	Short	Gen1	SigTest	1.012 us (Min)	Pass	412.340 ns & 387.660 ns	600.0 ns	1.4 us
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-29								

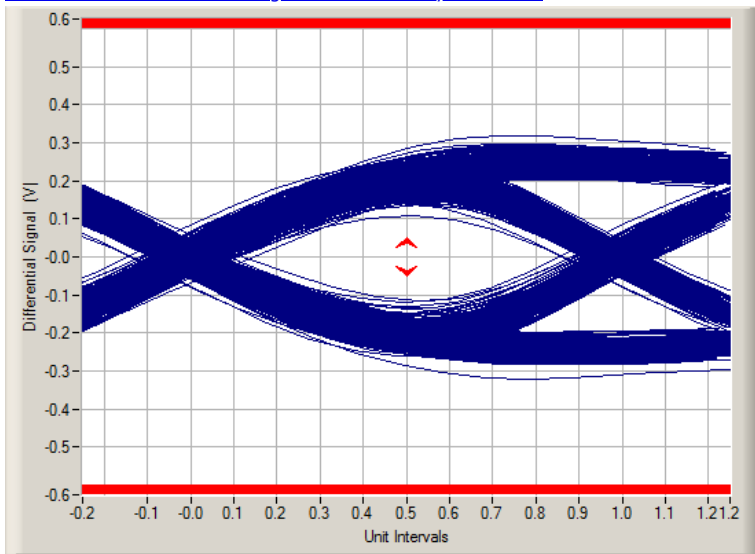
LFPS TRepeat									
Measurement Details	Lane	Channel	Generation	Method	Measured Value	Test Result	Margin	Low Limit	High Limit
LFPS TRepeat (Max)	Lane1	Short	Gen1	SigTest	12.040 us (Max)	Pass	6.040 us & 1.960 us	6.0 us	14.0 us
LFPS TRepeat (Min)	Lane1	Short	Gen1	SigTest	7.022 us (Min)	Pass	1.022 us & 6.978 us	6.0 us	14.0 us
COMMENTS	USB 3.1 Specification, Rev 1.0, Table 6-29								

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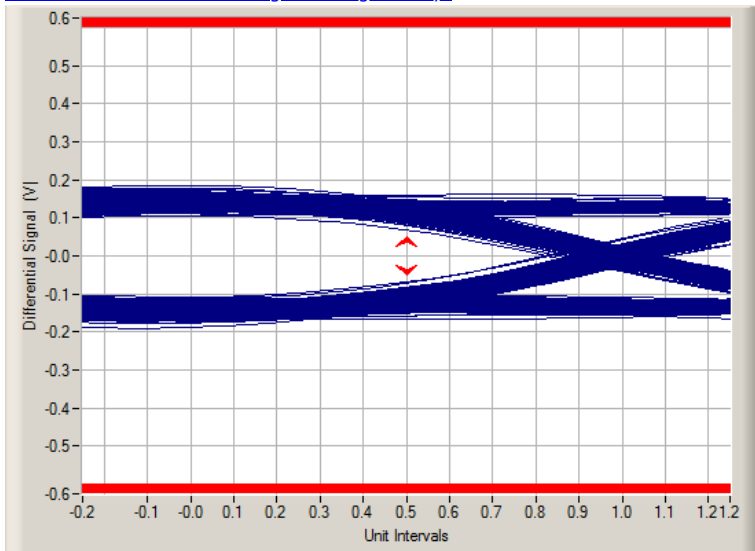
Mask Hits									
CP0_Lane1_Measured_Gen1_SigTest_Short_Run1Eye									



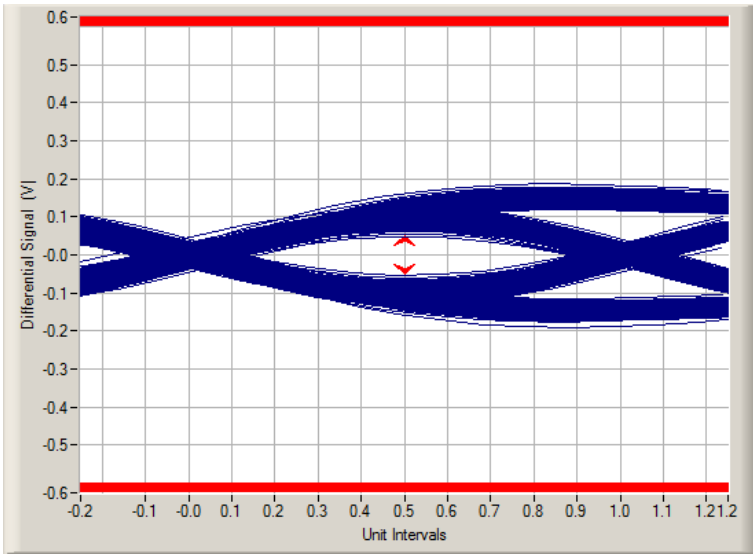
[CP0_Lane1_Measured_Gen1_SigTest_Short_Run1EyeTransition](#)



[CP0_Lane1_Measured_Gen1_SigTest_Long_Run1Eye](#)

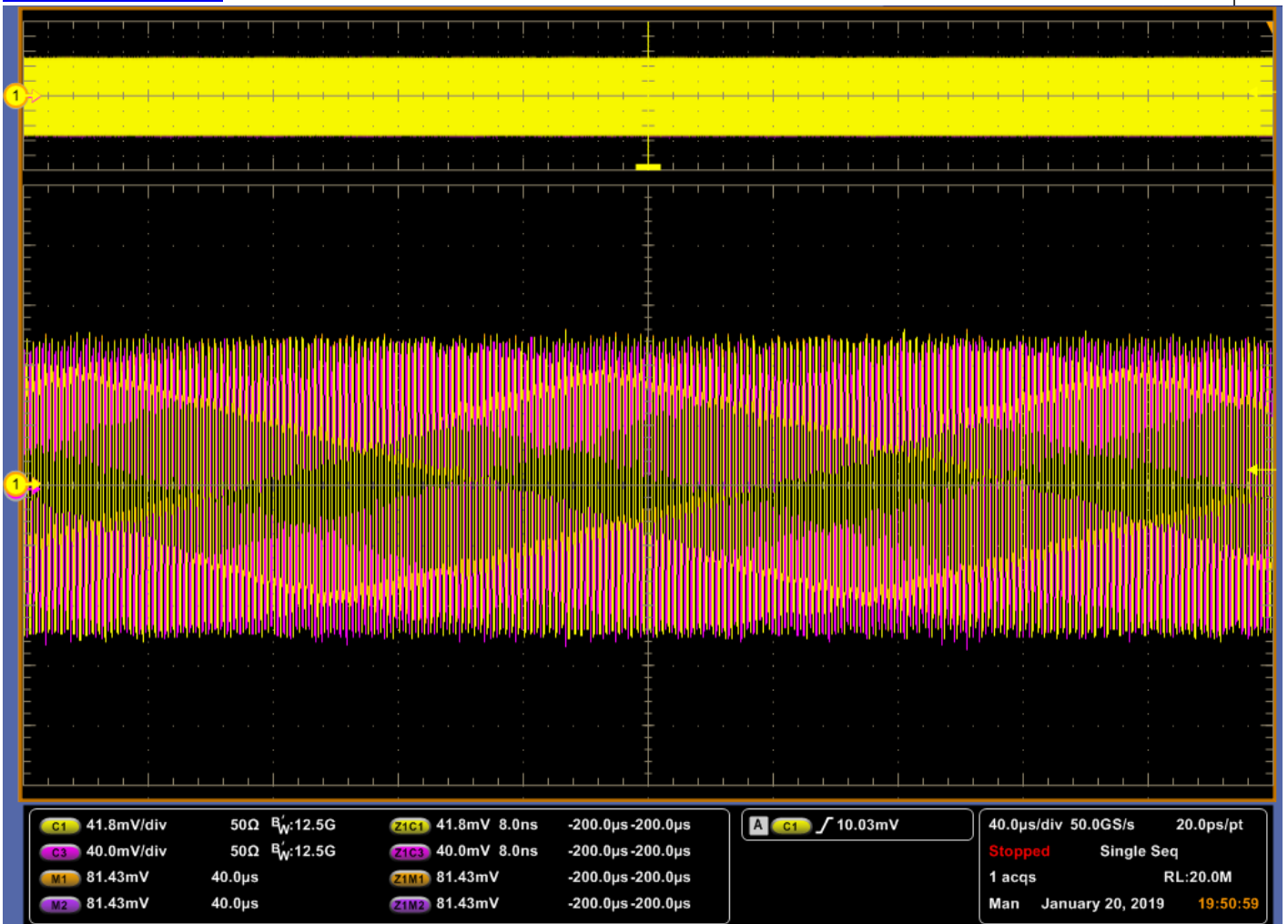


[CP0_Lane1_Measured_Gen1_SigTest_Long_Run1EyeTransition](#)

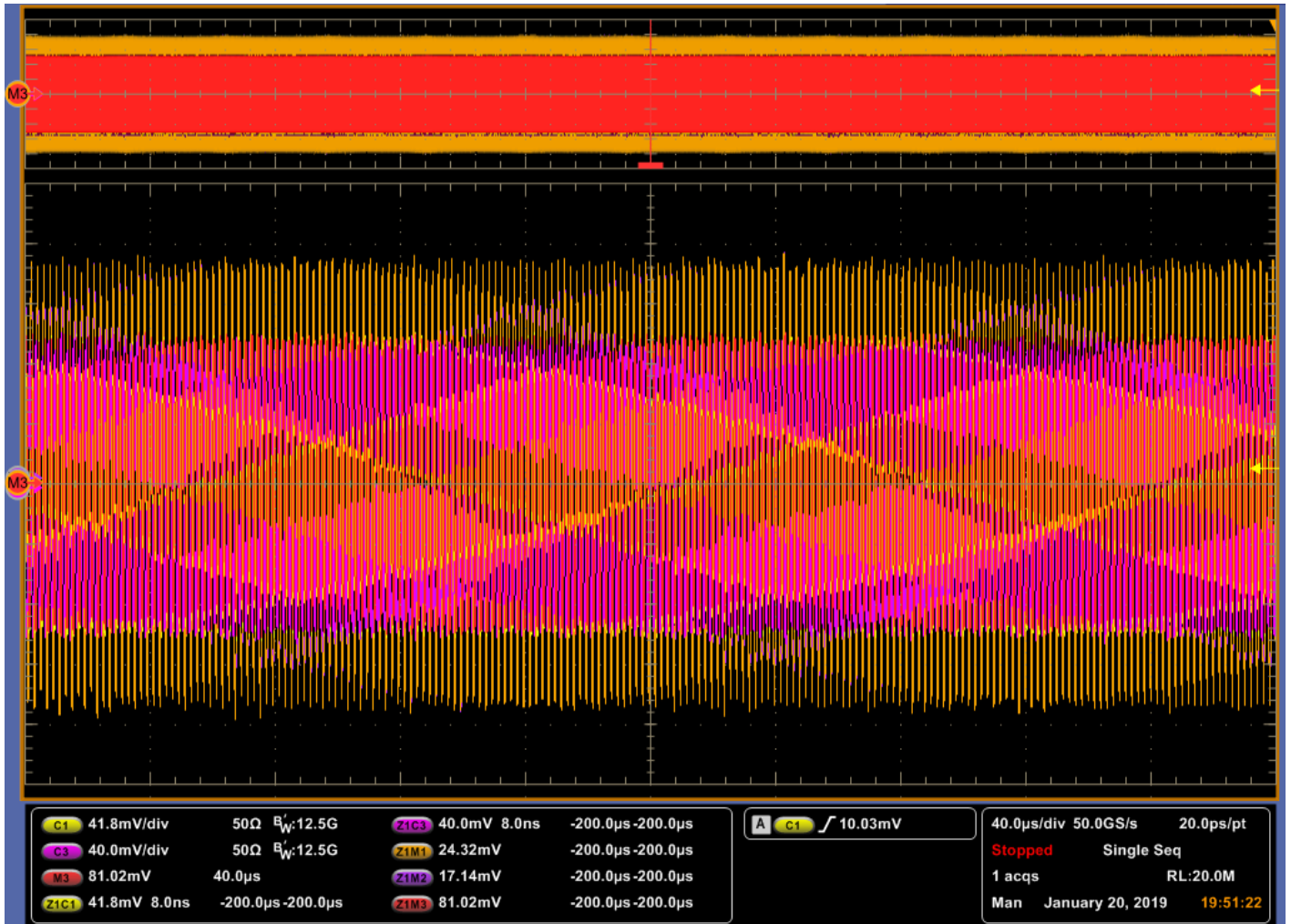


TSSC-Mod-Rate - SSC Modulation rate

[CPI waveform Shortchannel](#)

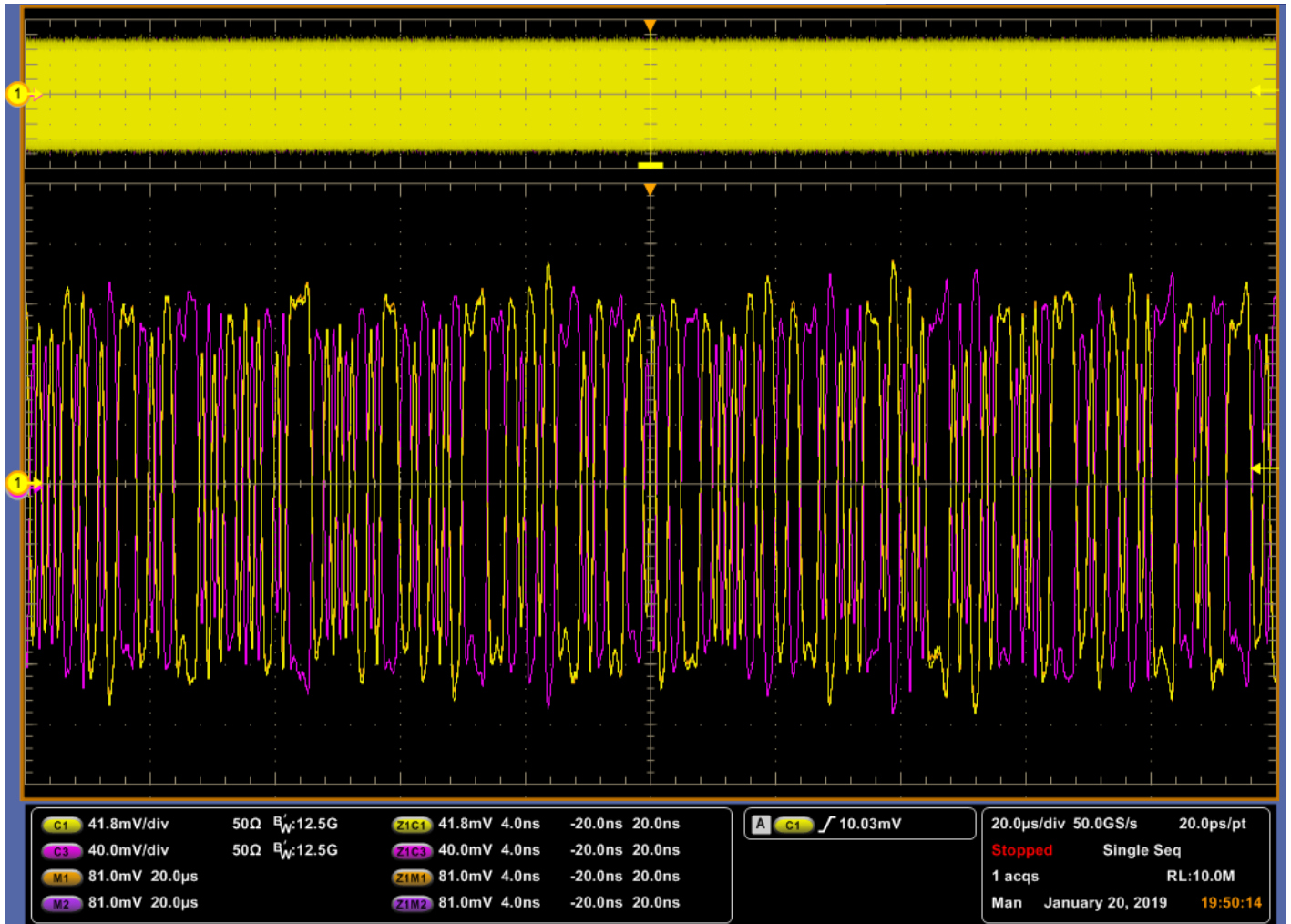


[CPI waveform Longchannel](#)



Eye Width @ 1E-12 BER

[CP0 waveform Shortchannel](#)



CP0 waveform Longchannel



LFPS Duty Cycle

LFPS waveform Shortchannel

